



Sheet 1 of 1

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## INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

## APPLICANT

Mutsumi KIMURA

FILING DATE  
July 9, 2003

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

## FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

AS	1	Shimoda et al., "High Resolution Light Emitting Polymer Display Driven by Low Temperature Polysilicon Thin Film Transistor with Integrated Driver," Proceeding of Asia Display, pp. 217, 1998
	2	Kimura et al., "Low-Temperature Polysilicon Thin-Film Transistor Driving with Integrated Driver for High-Resolution Light Emitting Polymer Display," IEEE Transactions on Electron Devices, Vol. 46, No. 12, pp. 2282-2288, December 1999
	3	Shimoda et al., "Current Status and Future of Light-Emitting Polymer Display Driven by Poly-Si TFT," SID 99 Digest, pp.372-375, 1999
	4	Kimura et al., "TFT-LEPD with Image Uniformity by Area Ratio Gray Scale," Proceeding of Euro. Display, pp. 71-74,
	5	Kimura et al., "Low-Temperature Poly-Si TFT Driven Light-Emitting-Polymer Displays and Digital Gray Scale for Uniformity," Proceeding of IDW, pp. 171-174, 1999
	6	Tam et al., "Polysilicon TFT Drivers for Light Emitting Polymer Displays," IDW, pp. 175-178, 1999
	7	Kimura et al., "An area-ratio gray-scale method to achieve image uniformity in TFT-LEPDs," Journal of the SID 8/2, pp. 93-97, 2000
	8	Kimura et al., "Low-Temperature Poly-Si TFT Display using Light-Emitting-Polymer," AM-LCD, pp. 245-248, 2000
	9	Tam et al., "Improved Polysilicon TFT Drivers for Light Emitting Polymer Displays," IDW, pp. 243-246, 2000
	10	Inoue et al., "Investigation of the Relationship between Hot-Carrier Degradation and Kink Effect in Low-Temperature Poly-Si TFTs," SID Digest, pp. 452-455, 1999
	11	Uraoka et al., "Hot Carrier Effects in Low-Temperature poly-Si p-ch TFTs under Dynamic Stress," AM-LCD, pp. 179-182, 2001
	12	Ohno et al., "Device Simulation of Reliability in Low Temperature Poly-Si TFTs," Technical Report of IEICE, pp. 43-49, 2000

EXAMINER

DATE CONSIDERED

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: December 29, 2003